

20V N-Channel Enhancement Mode MOSFET

Description

The AP2312BI uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

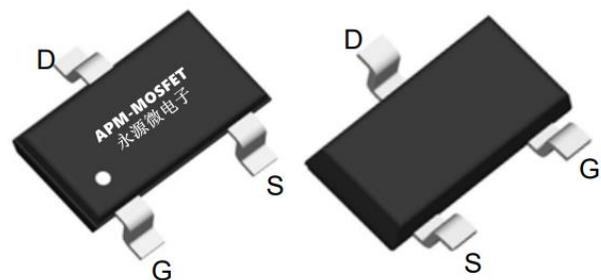
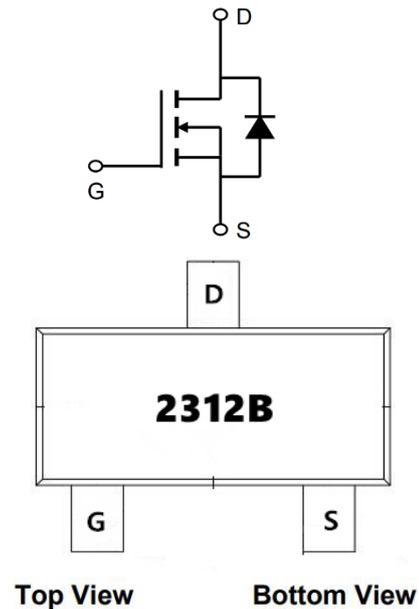
$V_{DS}=20V$ $I_D=6.2A$

$R_{DS(ON)} < 20m\Omega$ @ $V_{GS}=4.5V$ (Type: 16m Ω)

Application

Lithium battery protection

Mobile phone fast charging



Package Marking and Ordering Information

| Product ID | Pack | Marking | Qty(PCS) |
|------------|--------|---------|----------|
| AP2312BI | SOT23L | 2312B | 3000 |

Absolute Maximum Ratings ($T_A=25^\circ C$ unless otherwise noted)

| Symbol | Parameter | Rating | Units |
|------------------------|--|------------|--------------|
| VDS | Drain-Source Voltage | 20 | V |
| VGS | Gate-Source Voltage | ± 12 | V |
| $I_{D@T_A=25^\circ C}$ | Continuous Drain Current ¹ | 6.2 | A |
| $I_{D@T_A=70^\circ C}$ | Continuous Drain Current ¹ | 4.1 | A |
| IDM | Pulsed Drain Current ² | 24 | A |
| $PD@T_A=25^\circ C$ | Total Power Dissipation ³ | 1.5 | W |
| TSTG | Storage Temperature Range | -55 to 150 | $^\circ C$ |
| TJ | Operating Junction Temperature Range | -55 to 150 | $^\circ C$ |
| $R_{\theta JA}$ | Thermal Resistance Junction-ambient ¹ | 85 | $^\circ C/W$ |



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Electrical Characteristics ($T_J=25^\circ\text{C}$, unless otherwise noted)

| Symbol | Parameter | Conditions | Min. | Typ. | Max. | Unit |
|---------|--|---|------|------|------|------|
| BVDSS | Drain-Source Breakdown Voltage | $V_{GS}=0V, I_D=250\mu A$ | 20 | 22 | --- | V |
| RDS(ON) | Static Drain-Source On-Resistance ² | $V_{GS}=4.5V, I_D=5A$ | | 16 | 20 | mΩ |
| RDS(ON) | Static Drain-Source On-Resistance ² | $V_{GS}=2.5V, I_D=4A$ | | 22 | 30 | |
| VGS(th) | Gate Threshold Voltage | $V_{GS}=V_{DS}, I_D=250\mu A$ | 0.5 | 0.7 | 1.2 | V |
| IDSS | Drain-Source Leakage Current | $V_{DS}=16V, V_{GS}=0V, T_J=25^\circ\text{C}$ | --- | --- | 1 | μA |
| IGSS | Gate-Source Leakage Current | $V_{GS}=\pm 8V, V_{DS}=0V$ | --- | --- | ±100 | nA |
| gfs | Forward Transconductance | $V_{DS}=5V, I_D=3.5A$ | --- | 20 | --- | S |
| Qg | Total Gate Charge (4.5V) | $V_{DS}=15V, V_{GS}=4.5V, I_D=7A$ | --- | 11.4 | --- | nC |
| Qgs | Gate-Source Charge | | --- | 1.6 | --- | |
| Qgd | Gate-Drain Charge | | --- | 2.9 | --- | |
| Td(on) | Turn-On Delay Time | $V_{DD}=10V, V_{GS}=4.5V, R_G=3.3, I_D=5A$ | --- | 5 | --- | ns |
| Tr | Rise Time | | --- | 32.4 | --- | |
| Td(off) | Turn-Off Delay Time | | --- | 28 | --- | |
| Tf | Fall Time | | --- | 9 | --- | |
| Ciss | Input Capacitance | $V_{DS}=15V, V_{GS}=0V, f=1\text{MHz}$ | --- | 863 | --- | pF |
| Coss | Output Capacitance | | --- | 87 | --- | |
| Crss | Reverse Transfer Capacitance | | --- | 71 | --- | |
| IS | Continuous Source Current ^{1,4} | $V_G=V_D=0V, \text{Force Current}$ | --- | --- | 6 | A |
| VSD | Diode Forward Voltage ² | $V_{GS}=0V, I_S=1A, T_J=25^\circ\text{C}$ | --- | --- | 1.2 | V |

Note :

- 1、The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2、The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$
- 4、The power dissipation is limited by 175°C junction temperature
- 5、The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

Typical Characteristics

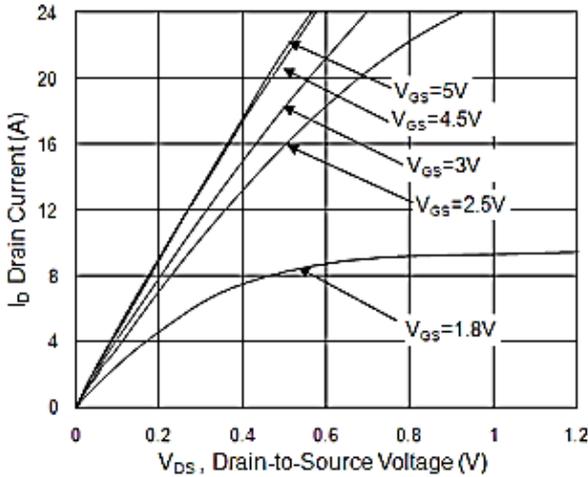


Fig.1 Typical Output Characteristics

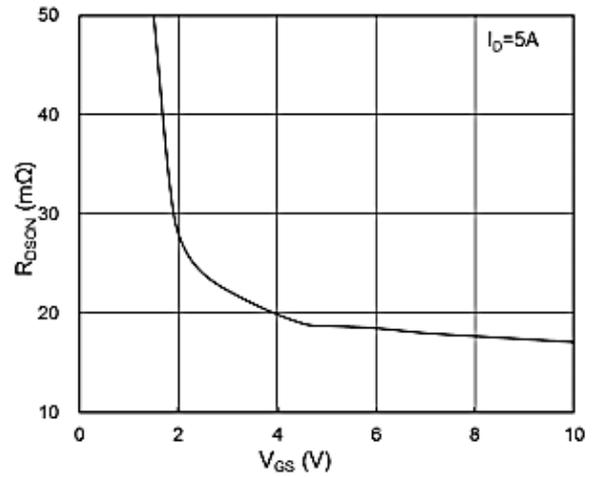


Fig.2 On-Resistance vs. Gate-Source Voltage

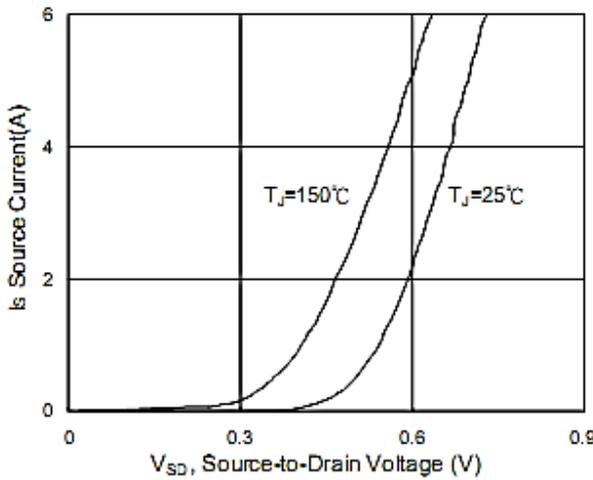


Fig.3 Forward Characteristics of Reverse

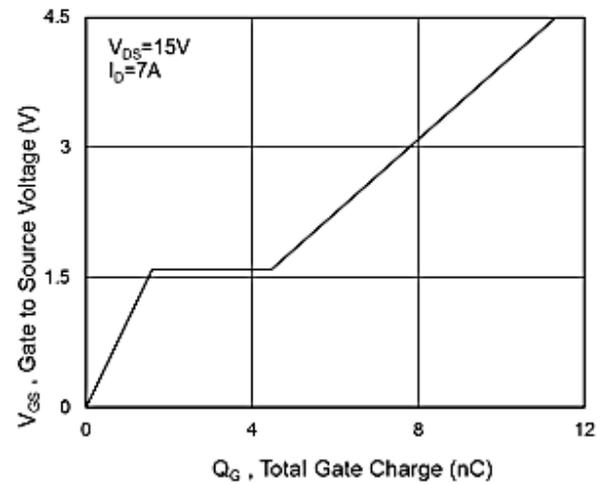


Fig.4 Gate-Charge Characteristics

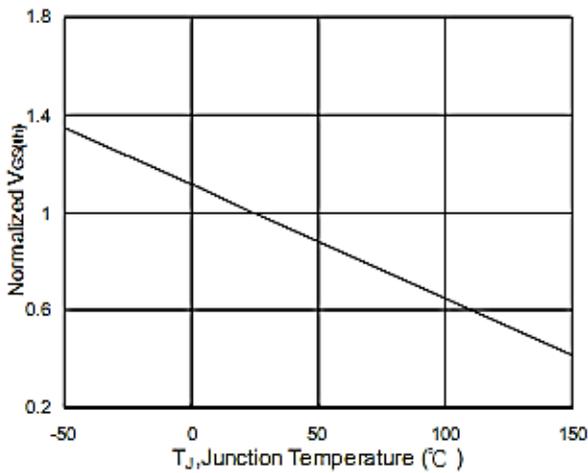


Fig.5 $V_{GS(th)}$ vs. T_J

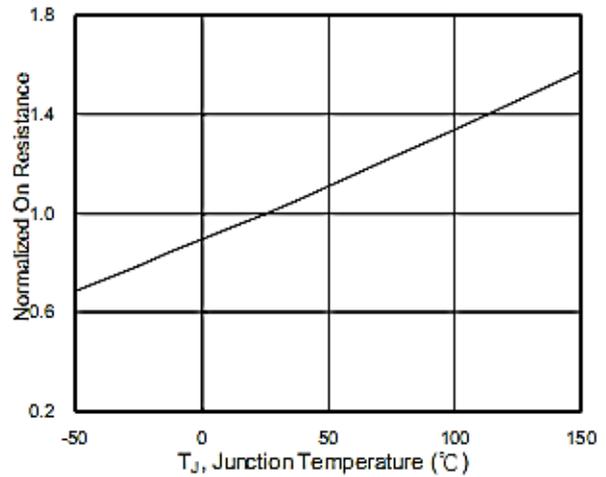


Fig.6 Normalized $R_{DS(on)}$ vs. T_J

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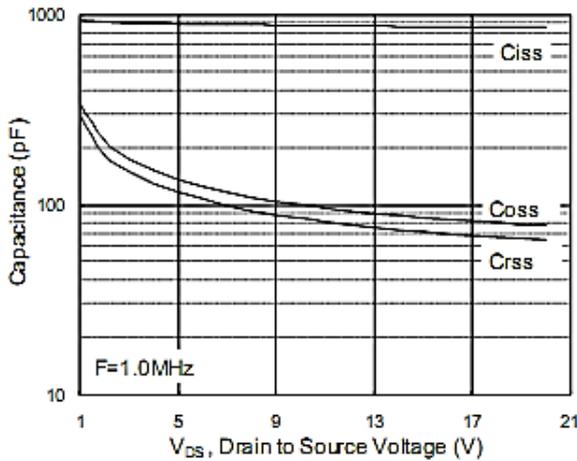


Fig.7 Capacitance

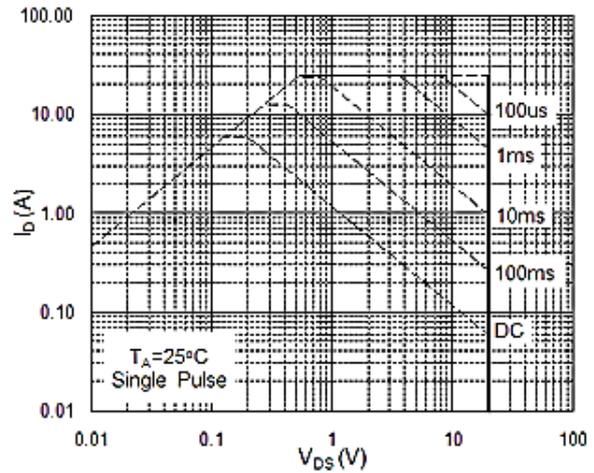


Fig.8 Safe Operating Area

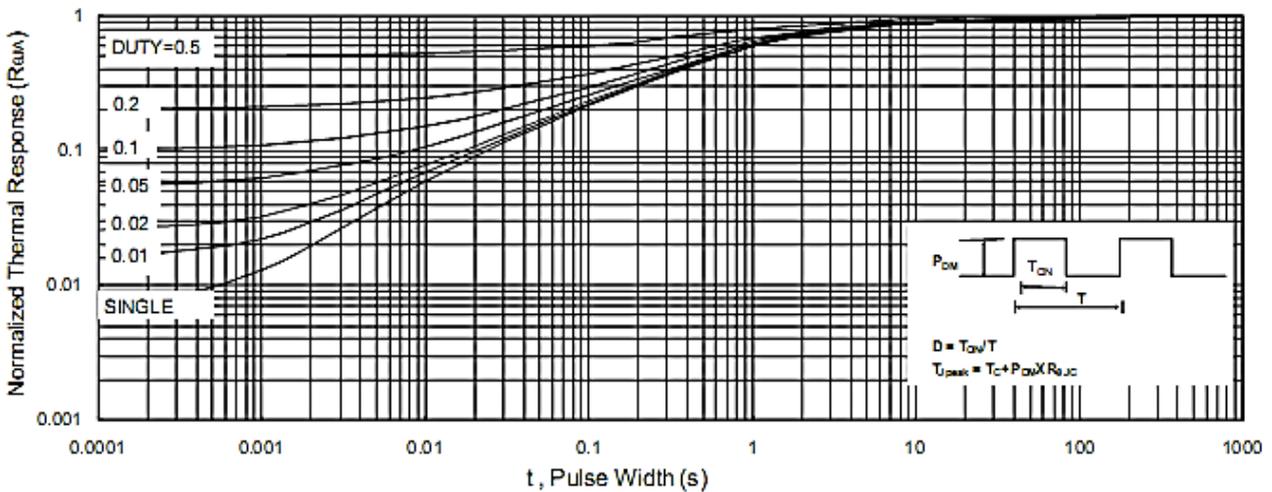


Fig.9 Normalized Maximum Transient Thermal Impedance

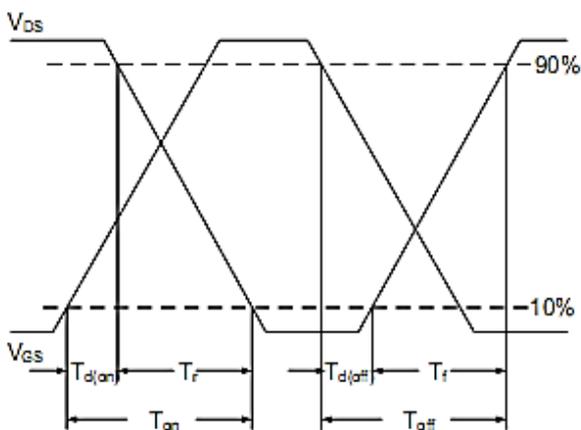


Fig.10 Switching Time Waveform

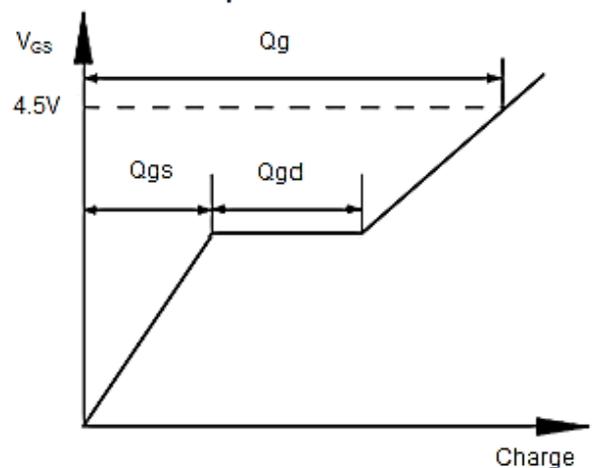
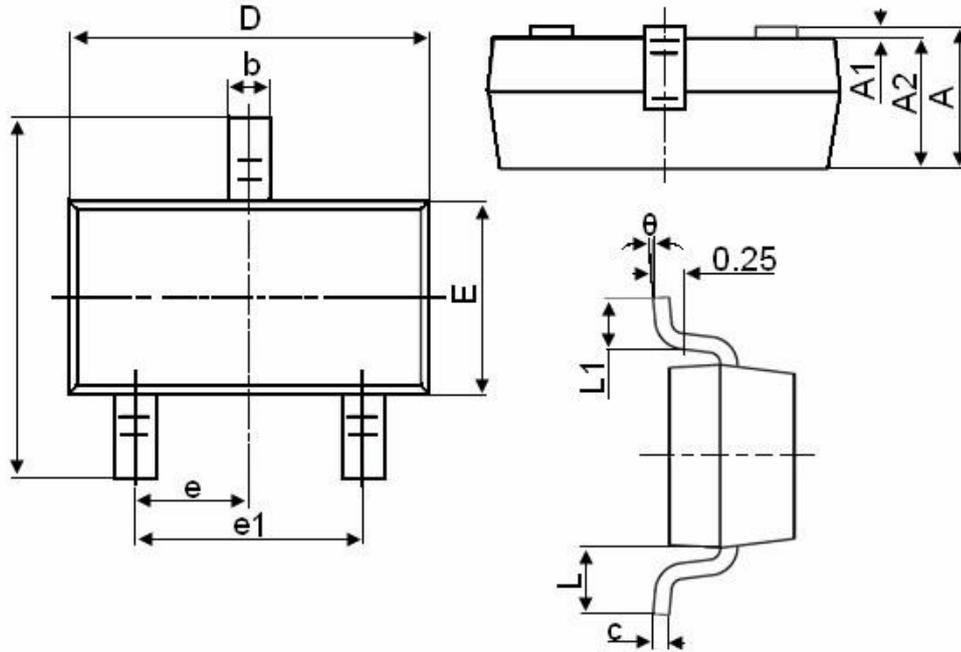


Fig.11 Gate Charge Waveform

Package Mechanical Data-SOT23-XC-Single



| Symbol | Dimensions in Millimeters | |
|----------|---------------------------|-------|
| | MIN. | MAX. |
| A | 0.900 | 1.150 |
| A1 | 0.000 | 0.100 |
| A2 | 0.900 | 1.050 |
| b | 0.300 | 0.500 |
| c | 0.080 | 0.150 |
| D | 2.800 | 3.000 |
| E | 1.200 | 1.400 |
| E1 | 2.250 | 2.550 |
| e | 0.950TYP | |
| e1 | 1.800 | 2.000 |
| L | 0.550REF | |
| L1 | 0.300 | 0.500 |
| θ | 0° | 8° |

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| Edition | Date | Change |
|---------|-----------|-----------------|
| Rve1.0 | 2020/1/31 | Initial release |

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